

Amendments to the claims:

This listing of claims will replace all prior versions, and listings, of claims in the application:

Listing of Claims:

1. (ORIGINAL) A method for inspecting a secondary battery precursor including a pair of electrodes and a separator disposed between the pair of electrodes, comprising:

applying a constant inspection voltage between the pair of electrodes before an electrolyte solution is injected between the pair of electrodes, and measuring a current flowing due to application of the inspection voltage; and

determining the precursor to be defective if a current value exceeding a previously set reference current value is detected within a time period corresponding to a time period between starting of voltage application when a voltage is applied to a normal secondary battery precursor and obtaining of a constant current.

2. (ORIGINAL) The method for inspecting a secondary battery precursor according to claim 1, wherein the reference current value is set based on a current when a voltage is applied to a normal secondary battery precursor.

3. (ORIGINAL) The method for inspecting a secondary battery precursor according to claim 1, wherein a plurality of reference current values are set depending upon time.

4. (ORIGINAL) The method for inspecting a secondary battery precursor according to claim 3, wherein the reference current values are set at intervals of 1 ms or less.

5. (CURRENTLY AMENDED) A method for inspecting a secondary battery precursor including a pair of electrodes and a separator disposed between the pair of electrodes, comprising:

~~applying an inspection voltage between the pair of electrodes before an electrolyte solution is injected between the pair of electrodes, and measuring a current flowing due to application of the inspection voltage; and~~

~~determining the precursor to be defective if the current has a value beyond a predetermined allowable range calculated based on a current waveform when a voltage is applied to a normal secondary battery precursor according to claim 1, wherein the inspection voltage is less than 75 V per 1 μm thickness of the separator.~~

6. (CURRENTLY AMENDED) The method for inspecting a secondary battery precursor according to claim 5, wherein the inspection voltage is a constant voltage claim 1, wherein the inspection voltage is less than 35 V per 1 μm thickness of the separator.

7. (CURRENTLY AMENDED) The method for inspecting a secondary battery precursor according to claim 5, wherein the inspection voltage is increased at a constant speed claim 1, wherein the inspection voltage is 420 V or more.

8. (CURRENTLY AMENDED) A method for inspecting a secondary battery precursor including a pair of electrodes and a separator disposed between the pair of electrodes, comprising:

~~applying an inspection current between the pair of electrodes before an electrolyte solution is injected between the pair of electrodes, and measuring a voltage due to application of the inspection current; and~~

~~determining the precursor to be defective if the voltage has a value beyond a predetermined allowable range calculated based on a voltage waveform when a current is applied to a normal secondary battery precursor according to claim 1, wherein the separator has a thickness of 25 μm or less.~~

9. (CURRENTLY AMENDED) The method for inspecting a secondary battery precursor according to claim 8, wherein the inspection current is a constant current claim 1, wherein the secondary battery precursor is a precursor of a lithium secondary battery.

10. (CURRENTLY AMENDED) The A method for inspecting a secondary battery precursor according to any one of claims 1 to 7, wherein the inspection voltage is less than 75 V per 1 μm thickness of the separator including a pair of electrodes and a separator disposed between the pair of electrodes, comprising:

applying an inspection voltage between the pair of electrodes before an electrolyte solution is injected between the pair of electrodes, and measuring a current flowing due to application of the inspection voltage; and

determining the precursor to be defective if the current has a value beyond a predetermined allowable range calculated based on a current waveform when a voltage is applied to a normal secondary battery precursor.

11. (CURRENTLY AMENDED) The method for inspecting a secondary battery precursor according to ~~any one of claims 1 to 7, wherein the inspection voltage is less than 35 V per 1 μ m thickness of the separator~~ claim 10, wherein the inspection voltage is a constant voltage.

12. (CURRENTLY AMENDED) The method for inspecting a secondary battery precursor according to ~~any one of claims 1 to 7, wherein the inspection voltage is 420 V or more~~ claim 10, wherein the inspection voltage is increased at a constant speed.

13. (CURRENTLY AMENDED) The method for inspecting a secondary battery precursor according to ~~any one of claims 1 to 9, wherein the separator has a thickness of 25 μ m or less~~ claim 10, wherein the inspection voltage is less than 75 V per 1 μ m thickness of the separator.

14. (CURRENTLY AMENDED) The method for inspecting a secondary battery precursor according to ~~any one of claims 1 to 9, wherein the secondary battery precursor is a precursor of a lithium secondary battery~~ claim 10, wherein the inspection voltage is less than 35 V per 1 μ m thickness of the separator.

15. (CURRENTLY AMENDED) A The method for manufacturing a secondary battery;
~~comprising:~~

~~manufacturing a secondary battery precursor including a pair of electrodes and a separator disposed between the pair of electrodes; and~~

~~inspecting the secondary battery precursor by the inspection method according to any one of claims 1 to 9~~ according to claim 10, wherein the inspection voltage is 420 V or more.

16. (CURRENTLY AMENDED) A device The method for inspecting a secondary battery precursor including a pair of electrodes, and a separator disposed between the pair of electrodes, comprising:

~~voltage application means for applying a voltage between the pair of electrodes;~~

~~current measurement means for measuring a current flowing due to application of the voltage;~~

~~storage means for storing a reference current value set based on a current when a voltage is applied to a normal secondary battery precursor; and~~

~~arithmetic operation means for performing a predetermined arithmetic operation using the reference current value stored in the storage means and a value of the current measured by the current measurement means, so as to determine whether the secondary battery precursor is defective or not according to claim 10, wherein the separator has a thickness of 25 μm or less.~~

17. (CURRENTLY AMENDED) The device method for inspecting a secondary battery precursor according to claim 16, wherein the current measurement means is an oscilloscope claim 10, wherein the secondary battery precursor is a precursor of a lithium secondary battery.

18. (CURRENTLY AMENDED) A device method for inspecting a secondary battery precursor including a pair of electrodes, and a separator disposed between the pair of electrodes, comprising:

~~current application means for applying a current between the pair of electrodes;~~

~~storage means for storing a reference voltage value set based on a voltage when a current is applied to a normal secondary battery precursor; and~~

~~arithmetic operation means for performing a predetermined arithmetic operation using the reference voltage value stored in the storage means and a value of the voltage measured by the voltage measurement means, so as to determine whether the secondary battery precursor is defective or not~~ applying an inspection current between the pair of electrodes before an electrolyte solution is injected between the pair of electrodes, and measuring a voltage due to application of the inspection current; and

determining the precursor to be defective if the voltage has a value beyond a predetermined allowable range calculated based on a voltage waveform when a current is applied to a normal secondary battery precursor.

19. (CURRENTLY AMENDED) The ~~device~~ method for inspecting a secondary battery precursor according to claim 18, wherein the ~~voltage measurement means is an oscilloscope~~ inspection current is a constant current.

20. (NEW) The method for inspecting a secondary battery precursor according to claim 18, wherein the separator has a thickness of 25 μm or less.

21. (NEW) The method for inspecting a secondary battery precursor according to claim 18, wherein the secondary battery precursor is a precursor of a lithium secondary battery.

22. (NEW) A method for manufacturing a secondary battery, comprising:

manufacturing a secondary battery precursor including a pair of electrodes and a separator disposed between the pair of electrodes; and
inspecting the secondary battery precursor by the inspection method according to claim 1.

23. (NEW) A method for manufacturing a secondary battery, comprising:

manufacturing a secondary battery precursor including a pair of electrodes and a separator disposed between the pair of electrodes; and
inspecting the secondary battery precursor by the inspection method according to claim 10.

24. (NEW) A method for manufacturing a secondary battery, comprising:

manufacturing a secondary battery precursor including a pair of electrodes and a separator disposed between the pair of electrodes; and
inspecting the secondary battery precursor by the inspection method according to claim 18.

25. (NEW) A device for inspecting a secondary battery precursor including a pair or electrodes, and a separator disposed between the pair of electrodes, comprising:

voltage application means for applying a voltage between the pair of electrodes;
current measurement means for measuring a current flowing due to application of the voltage;
storage means for storing a reference current value set based on a current when a voltage is applied to a normal secondary battery precursor; and

arithmetic operation means for performing a predetermined arithmetic operation using the reference current value stored in the storage means and a value of the current measured by the current measurement means, so as to determine whether the secondary battery precursor is defective or not.

26. (NEW) The device for inspecting a secondary battery precursor according to claim 25, wherein the current measurement means is an oscilloscope.

27. (NEW) A device for inspecting a secondary battery precursor including a pair of electrodes, and a separator disposed between the pair of electrodes, comprising:

current application means for applying a current between the pair of electrodes;

voltage measurement means for measuring a voltage generated due to application of the current;

storage means for storing a reference voltage value set based on a voltage when a current is applied to a normal secondary battery precursor; and

arithmetic operation means for performing a predetermined arithmetic operation using the reference voltage value stored in the storage means and a value of the voltage measured by the voltage measurement means, so as to determine whether the secondary battery precursor is defective or not.

28. (NEW) The device for inspecting a secondary battery precursor according to claim 27, wherein the voltage measurement means is an oscilloscope.